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Contents

vii *Conference Committee*

SESSION 1 SAPHIRE AND ALUMINA

- 7302 02 **Evolution of the sapphire industry: Rubicon Technology and Gavish** [7302-01]
D. C. Harris, Naval Air Systems Command (United States)
- 7302 03 **Characteristics of thick (>12 mm) Class²²⁵ EFG sapphire sheet for IR window applications**
[7302-02]
J. Locher, C. Jones, H. Bates, J. Rioux, Saint-Gobain Crystals (United States)
- 7302 04 **Hydrogen effect on the properties of sapphire** [7302-03]
R. N. Mogilevsky, L. G. Sharafutdinova, Emerging Material Technologies, Inc. (United States);
S. Nediiko, Kyiv National Taras Shevchenko Univ. (Ukraine); V. Gavrilov, JSC Technocrystal
(Ukraine); D. Verbilo, Frantsevich Institute for Problems of Materials Science (Ukraine);
S. D. Mittl, Insaco, Inc. (United States)
- 7302 05 **Polycrystalline alumina for aerodynamic IR domes and windows** [7302-04]
M. V. Parish, M. R. Pascucci, CeraNova Corp. (United States)

SESSION 2 MULTIFUNCTIONAL WINDOWS AND DOMES: EVOLVING OPTICAL CHALLENGES

- 7302 06 **Large-area ALON windows for reconnaissance and armor applications** [7302-06]
L. M. Goldman, R. Twedt, R. Foti, M. Smith, S. A. Sastri, Surmet Corp. (United States)
- 7302 07 **Dual IR/RF windows for laser communications** [7302-07]
L. M. Goldman, R. Twedt, J. Zigman, Surmet Corp. (United States); R. Ondercin, Air Force
Research Lab. (United States)
- 7302 08 **Joining transparent ceramics** [7302-08]
A. Shechter, B. Bloch, E. Galun, Elbit Systems Electro-Optics El-Op Ltd. (Israel)
- 7302 09 **Processing method and process modeling of large aperture transparent magnesium
aluminate spinel domes** [7302-09]
J. Yu, B. McWilliams, S. Kilczewski, G. Gilde, A. Lidie, J. Sands, U.S. Army Research Lab. (United
States)
- 7302 0A **Bonding force determination at AFB interfaces of single crystal sapphire composites**
[7302-10]
H.-C. Lee, H. Meissner, X. Mu, Onyx Optics, Inc. (United States); C. Liu, W. Qiu, Valdosta
Optics Lab., Inc. (United States)

SESSION 3 SPINEL WINDOWS AND DOMES

- 7302 0B **Evaluation of commercially available bulk Mg and Al oxides and hydroxides for the production of transparent $MgAl_2O_4$** [7302-11]
A. C. Sutorik, G. Gilde, S. M. Kilczewski, A. Lidie, U.S. Army Research Lab. (United States)
- 7302 0C **Observations during the fabrication of spinel optics** [7302-12]
J. R. Bashe, D. L. Hibbard, Exotic Electro-Optics (United States)
- 7302 0D **Manufacturing issues for polycrystalline transparent spinel domes** [7302-13]
A. LaRoche, J. Kutsch, K. Rozenberg, L. Fehrenbacher, Technology Assessment and Transfer (United States)
- 7302 0E **Advances in spinel ceramic technology for large windows and domes** [7302-14]
J. L. Sepulveda, R. O. Louffy, S. Chang, S. Ibrahim, Materials and Electrochemical Research Corp. (United States); N. Traggis, Precision Photonics Corp. (United States)
- 7302 0F **Recent developments in transparent polycrystalline spinel for electro-optic applications** [7302-15]
I. Aggarwal, S. Bayya, G. Villalobos, W. Kim, J. Sanghera, Naval Research Lab. (United States)
- 7302 0G **High-strength transparent spinel with fine, unimodal grain size** [7302-16]
S. M. Sweeney, M. K. Brun, T. J. Yosenick, A. Kebbede, M. Manoharan, GE Global Research (United States)

SESSION 4 COATINGS AND SURFACE TREATMENTS

- 7302 0H **High growth rate deposition of highly oriented polycrystalline diamond film** [7302-17]
C. Liu, W. Qiu, Valdosta Optics Lab., Inc. (United States); H. Meissner, Onyx Optics, Inc. (USA)
- 7302 0I **Evaluating environmental survivability of optical coatings** [7302-18]
S. Joseph, D. Yadlovker, O. Marcovitch, H. Zipin, Rafael Advanced Defense Systems Ltd. (Israel)
- 7302 0J **Study of the environmental and optical durability of AR microstructures in sapphire, ALON, and diamond** [7302-20]
D. S. Hobbs, TelAztec LLC (United States)
- 7302 0K **Application of physical gradient index (Moth-Eye) structures to ALON windows as a durable anti-reflection treatment** [7302-21]
N. Agarwal, L. M. Goldman, S. A. Sastri, Surmet Corp. (United States); R. J. Ondercin, Air Force Research Lab. (United States); P. Kobrin, Teledyne Scientific & Imaging LLC (United States)

SESSION 5 GERMANIUM AND ZINC SULFIDE OPTICAL MATERIALS

- 7302 0L **A historical view of germanium as an infrared window material** [7302-22]
R. M. Sullivan, Office of Naval Research (United States)

- 7302 0M **Variability in chemical vapor deposited zinc sulfide: assessment of legacy and international CVD ZnS materials** [7302-24]
J. McCloy, Raytheon Missile Systems (United States); R. Korenstein, Raytheon Co. (United States)
- 7302 0N **The effect of metal on the formation of multispectral zinc sulfide** [7302-25]
J. McCloy, Raytheon Missile Systems (United States); R. Korenstein, Raytheon Co. (United States)
- 7302 0O **Varying electro-kinetic interactions to achieve predictable polishing results on zinc sulfide** [7302-26]
J. DeGroot Nelson, J. A. Drucker, A. A. Haefner, R. A. Wiederhold, Optimax Systems, Inc. (United States)

SESSION 6 METROLOGY

- 7302 0P **Instrumentation for characterizing a new class of optical domes** [7302-27]
A. K. Lal, J. S. Jo, S. Kupiec, E. Scott, J. Trolinger, MetroLaser, Inc. (United States)
- 7302 0Q **Round robin testing of the Optimax Optidome** [7302-28]
M. Martucci, R. Plympton, Optimax Systems, Inc. (United States)
- 7302 0R **Measurement results for time-delayed source interferometers for windows, hemispherical domes, and tangent ogives** [7302-29]
W. P. Kuhn, Opt-E (United States); M. B. Dubin, College of Optical Sciences, The Univ. of Arizona (United States); R. S. LeCompte, H. P. Durazo, Breault Research Organization, Inc. (United States)
- 7302 0S **An innovative non-contact surface measurement solution for asphere, deep parabolic, and ogive radome geometries** [7302-30]
S. DeFisher, M. Bechtold, D. Mohring, S. Bambrick, OptiPro Systems (United States)
- 7302 0T **Low-coherence surface metrology using a multiple-beam optical probe** [7302-31]
D. W. Diehl, C. J. Ditchman, C. T. Cotton, ASE Optics, Inc. (United States)

SESSION 7 CHARACTERIZATION AND FINISHING

- 7302 0U **Recent developments in finishing of deep concave, aspheric, and plano surfaces utilizing the UltraForm 5-axes computer controlled system** [7302-33]
S. Bambrick, M. Bechtold, S. DeFisher, D. Mohring, J. Meisenzahl, OptiPro Systems (United States)
- 7302 0V **Technologies for precision manufacture of current and future windows and domes** [7302-34]
B. Hallock, A. Shorey, QED Technologies (United States)
- 7302 0W **Semi-empirical scattering model for chemical vapor deposited zinc sulfide** [7302-35]
J. McCloy, Raytheon Missile Systems (United States)

- 7302 0X **Predicted and measured EMI shielding effectiveness of a metallic mesh coating on a sapphire window over a broad frequency range** [7302-36]
K. T. Jacoby, M. W. Pieratt, Exotic Electro-Optics, Inc. (United States); J. I. Halman, K. A. Ramsey, Battelle Memorial Institute (United States)
- 7302 0Y **Predicted and measured transmission and diffraction by a metallic mesh coating** [7302-37]
J. I. Halman, K. A. Ramsey, Battelle Memorial Institute (United States); M. Thomas, A. Griffin, Spica Technologies, Inc. (United States)
- 7302 0Z **Birefringence and grain-size effects on optical transmittance of polycrystalline magnesium fluoride** [7302-38]
T.-C. Wen, D. K. Shetty, The Univ. of Utah (United States)
- 7302 10 **Flexural strength of fused silica: Weibull statistical analysis** [7302-39]
C. A. Klein, C.A.K. Analytics, Inc. (United States)

SESSION 8 NOVEL MATERIALS

- 7302 11 **Low-thermal expansion infrared glass ceramics** [7302-40]
P. Lam, L2 Tech, Inc. (United States)
- 7302 12 **Optical properties of polycrystalline Nd:YAG for different levels of Nd doping** [7302-42]
R. M. Springer, Naval Air Systems Command (United States); M. E. Thomas, D. V. Hahn, The Johns Hopkins Univ. Applied Physics Lab. (United States); F. A. Narducci, Naval Air Systems Command (United States)
- 7302 13 **Onshore produced ceramic laser material development progress** [7302-43]
J. C. Huie Imholt, T. Hartnett, R. Gentilman, S. R. Silberstein, Raytheon Integrated Defense Systems (United States)
- 7302 14 **Advanced parylene technology for sensors, optical windows, and display applications** [7302-44]
R. Kumar, Specialty Coating Systems, Inc. (United States)

POSTER SESSION

- 7302 15 **Design and implementation of a new time-delayed source and alignment considerations for a tangent ogive interferometer** [7302-45]
H. P. Durazo, Breault Research Organization (United States); W. P. Kuhn, Opt-E (United States); R. S. LeCompte, Breault Research Organization (United States); M. B. Dubin, College of Optical Sciences, The Univ. of Arizona (United States)

Author Index

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Laboratory (United States)

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Session Chairs

- 1 Sapphire and Alumina
Daniel C. Harris, Naval Air Systems Command (United States)
- 2 Multifunctional Windows and Domes: Evolving Optical Challenges
Robert J. Ondercin, Air Force Research Laboratory (United States)
- 3 Spinel Windows and Domes
Joel Askinazi, Goodrich Corporation (United States)
- 4 Coatings and Surface Treatments
Richard Gentilman, Raytheon Company (United States)

- 5 Germanium and Zinc Sulfide Optical Materials
Adrienne E. Selz, Air Force Research Laboratory (United States)
- 6 Metrology
Ishwar D. Aggarwal, Naval Research Laboratory (United States)
- 7 Characterization and Finishing
Roger M. Sullivan, Office of Naval Research (United States)
- 8 Novel Materials
Michael E. Thomas, The Johns Hopkins University Applied Physics
Laboratory (United States)